BUK9213-30A



N-channel TrenchMOS logic level FET Rev. 02 — 18 February 2011

Product data sheet

Product profile 1.

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- AEC Q101 compliant
- Suitable for logic level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating

1.3 Applications

- 12 V loads
- Automotive and general purpose power switching
- Motors, lamps and solenoids

1.4 Quick reference data

Quick reference data Table 1.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 ^{\circ}\text{C}; T_j \le 175 ^{\circ}\text{C}$		-	-	30	V
I _D	drain current	V _{GS} = 5 V; T _{mb} = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>	[1]	-	-	75	Α
P _{tot}	total power dissipation	$T_{mb} = 25 ^{\circ}\text{C}$; see Figure 2		-	-	150	W
Static char	acteristics						
R _{DSon}	drain-source on-state	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}$		-	9	11	mΩ
	resistance	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}$		-	-	14.4	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 11}}{\text{see}};$ $\frac{\text{Figure 12}}{\text{Figure 12}}$		-	11	13	mΩ



Table 1. Quick reference data ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanche	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$\begin{split} I_D &= 55 \text{ A; } V_{sup} \leq 30 \text{ V;} \\ R_{GS} &= 50 \text{ \Omega; } V_{GS} = 5 \text{ V;} \\ T_{j(init)} &= 25 \text{ °C; } unclamped \end{split}$	-	-	467	mJ
Dynamic cl	naracteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 5 \text{ V; } I_D \text{ 25 A;}$ $V_{DS} = 24 \text{ V; } T_j = 25 \text{ °C;}$ see Figure 13	-	18	-	nC

^[1] Current is limited by power dissipation chip rating.

2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol		
1	G	gate		_		
2	D	drain	mb	D		
3	S	source				
mb	D	mounting base; connected to drain	1 3	mbb076 S		
			SOT428 (DPAK)			

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK9213-30A	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

		,			
Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	30	V
V_{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	30	V
V_{GS}	gate-source voltage		-15	15	V
I _D	drain current	$T_{mb} = 100 ^{\circ}C; V_{GS} = 5 V; \text{ see } \frac{\text{Figure 1}}{}$	<u>[1]</u> -	54	Α
		$T_{mb} = 25 ^{\circ}C; V_{GS} = 5 V; \text{ see } \frac{\text{Figure 1}}{};$	<u>[1]</u> -	75	Α
		see Figure 3	[2] _	55	Α
I _{DM}	peak drain current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \mu s$; see Figure 3	-	311	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	150	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-drai	n diode				
Is	source current	T _{mb} = 25 °C	<u>[1]</u> -	75	Α
			[2] -	55	Α
I _{SM}	peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$	-	311	Α
Avalanche r	ruggedness				
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	I_D = 55 A; $V_{sup} \le 30$ V; R_{GS} = 50 Ω; V_{GS} = 5 V; $T_{j(init)}$ = 25 °C; unclamped	-	467	mJ
		** *			

- [1] Current is limited by power dissipation chip rating.
- [2] Continuous current is limited by bondwires.

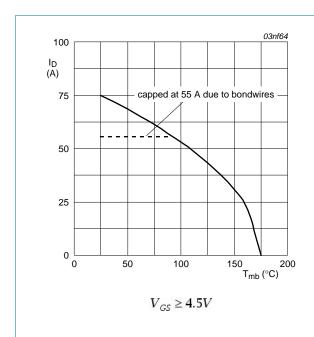


Fig 1. Continuous drain current as a function of mounting base temperature

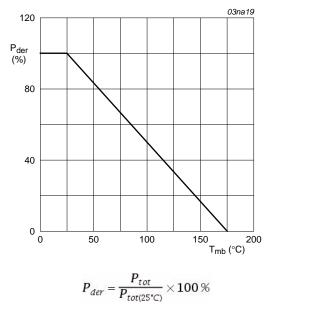
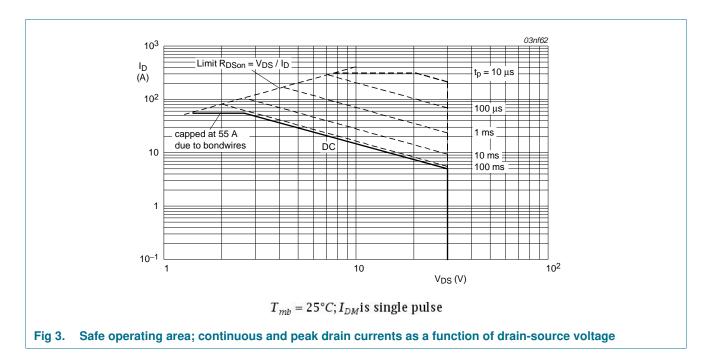


Fig 2. Normalized total power dissipation as a function of mounting base temperature

BUK9213-30A

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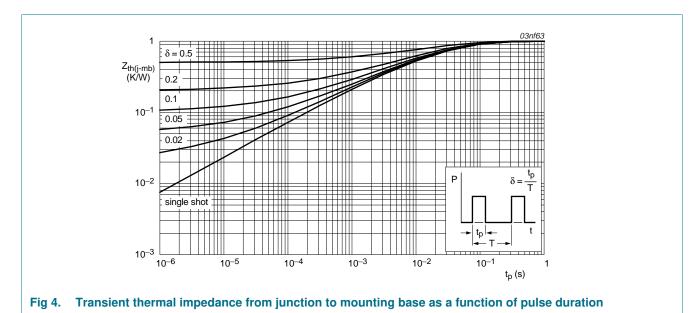
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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j\text{-}mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	0.56	1	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient		-	71.4	-	K/W



6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	30	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	27	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see Figure 10	-	-	2.3	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 175$ °C; see Figure 10	0.5	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see Figure 10	1	1.5	2	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	10	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
		$V_{GS} = -10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
R _{DSon}	drain-source on-state	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C}$	-	9	11	mΩ
resi	resistance	$V_{GS} = 5 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 175 \text{ °C}$; see Figure 11; see Figure 12	-	-	24	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C}$	-	-	14.4	mΩ
		$V_{GS} = 5 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 25 \text{ °C}$; see Figure 11; see Figure 12	-	11	13	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 24 \text{ V}; V_{GS} = 5 \text{ V};$	-	37	-	nC
Q_{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 13</u>	-	7	-	nC
Q_{GD}	gate-drain charge	I_D 25 A; V_{DS} = 24 V; V_{GS} = 5 V; T_j = 25 °C; see Figure 13	-	18	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	2140	2852	pF
C _{oss}	output capacitance	$T_j = 25 ^{\circ}\text{C}$; see Figure 14	-	550	660	pF
C _{rss}	reverse transfer capacitance		-	334	457	pF
d(on)	turn-on delay time	$V_{DS} = 20 \text{ V}; R_L = 2.7 \Omega; V_{GS} = 5 \text{ V};$	-	26	-	ns
t _r	rise time	$R_{G(ext)} = 10 \Omega; T_j = 25 °C$	-	202	-	ns
t _{d(off)}	turn-off delay time	$V_{DS} = 20 \text{ V}; R_L = 2.7 \Omega; V_{GS} = 5 \text{ V}; R_{G(ext)} = 10 \Omega; T_j 25 ^{\circ}\text{C}$	-	134	-	ns
i-f	fall time	V_{DS} = 20 V; R_L = 2.7 Ω ; V_{GS} = 5 V; $R_{G(ext)}$ = 10 Ω ; T_j = 25 °C	-	158	-	ns
-D	internal drain inductance	measured from drain to centre of die; $T_j = 25 ^{\circ}\text{C}$	-	2.5	-	nΗ
L _S	internal source inductance	measured from source lead to source bond pad; $T_j = 25 ^{\circ}\text{C}$	-	7.5	-	nΗ

Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-drain	diode					
V _{SD}	source-drain voltage	$I_S = 15 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 15</u>	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A}/\mu s;$	-	55	-	ns
Q _r	recovered charge	$V_{GS} = -10 \text{ V}; V_{DS} = 20 \text{ V}; T_j = 25 \text{ °C}$	-	24	-	nC

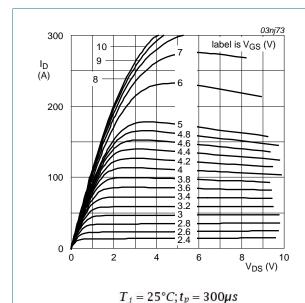


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

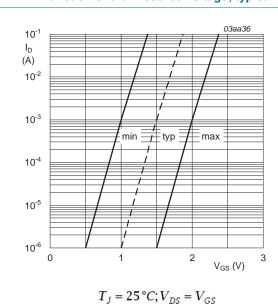
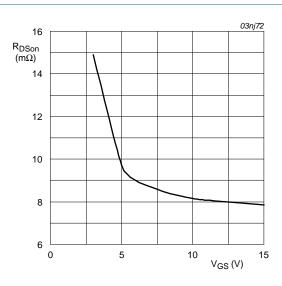
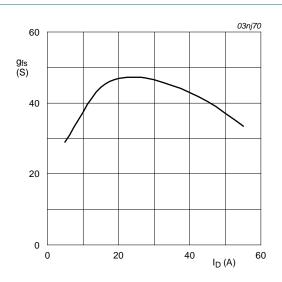


Fig 7. Sub-threshold drain current as a function of gate-source voltage



$$T_i = 25^{\circ}C; I_D = 25A$$

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values



 $T_j=25^{\circ}C; V_{DS}=25V$

Fig 8. Forward transconductance as a function of drain current; typical values

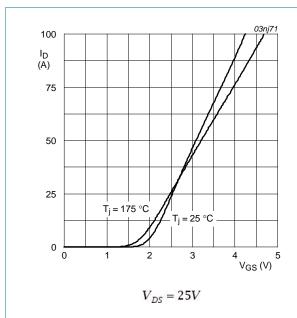


Fig 9. Transfer characteristics: drain current as a function of gate-source voltage; typical values

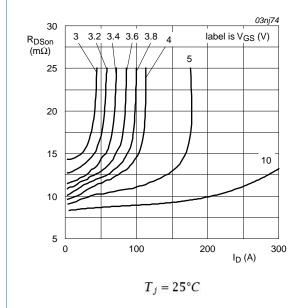


Fig 11. Drain-source on-state resistance as a function of drain current; typical values

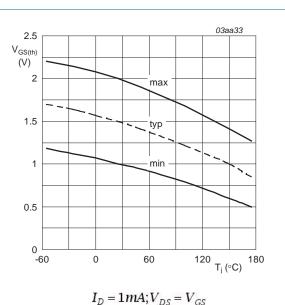


Fig 10. Gate-source threshold voltage as a function of junction temperature

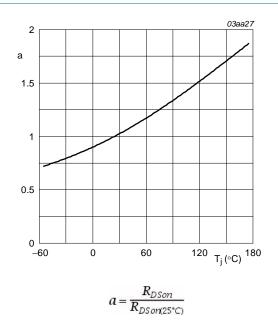


Fig 12. Normalized drain-source on-state resistance factor as a function of junction temperature

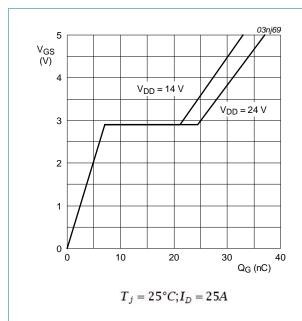
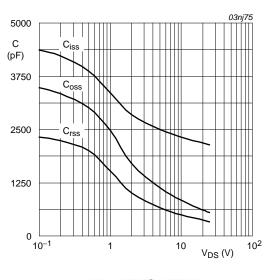
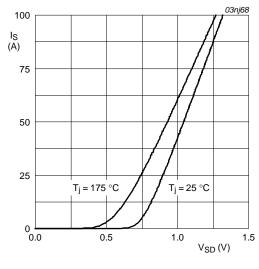


Fig 13. Gate-source voltage as a function of turn-on gate charge; typical values



 $V_{GS} = 0V; f = 1MHz$

Fig 14. Input and reverse transfer capacitances as a function of drain-source voltage; typical values



 $V_{GS} = 0V$

Fig 15. Reverse diode current as a function of reverse diode voltage; typical values

7. Package outline

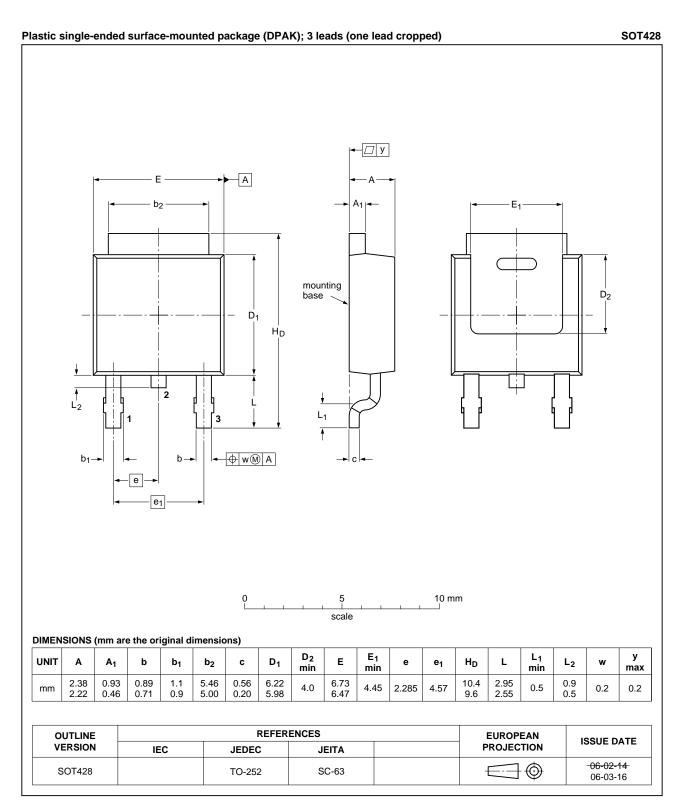


Fig 16. Package outline SOT428 (DPAK)

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK9213-30A v.2	20110218	Product data sheet	-	BUK9213-30A v.1
Modifications:	 The format of this data sheet has been redesigned to comply with the new identity guideline of NXP Semiconductors. 			
	 Legal texts hav 	e been adapted to the new	company name where	appropriate.
	 Various change 	es to content.		
BUK9213-30A v.1	20020729	Product data	-	-

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9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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